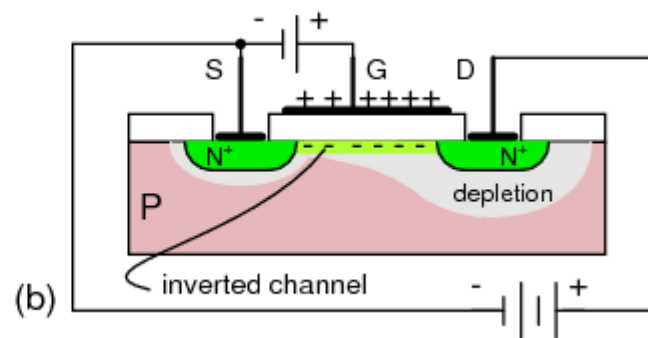
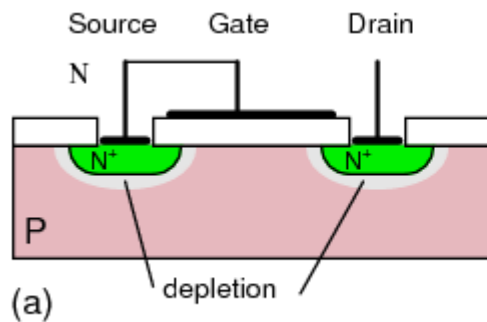
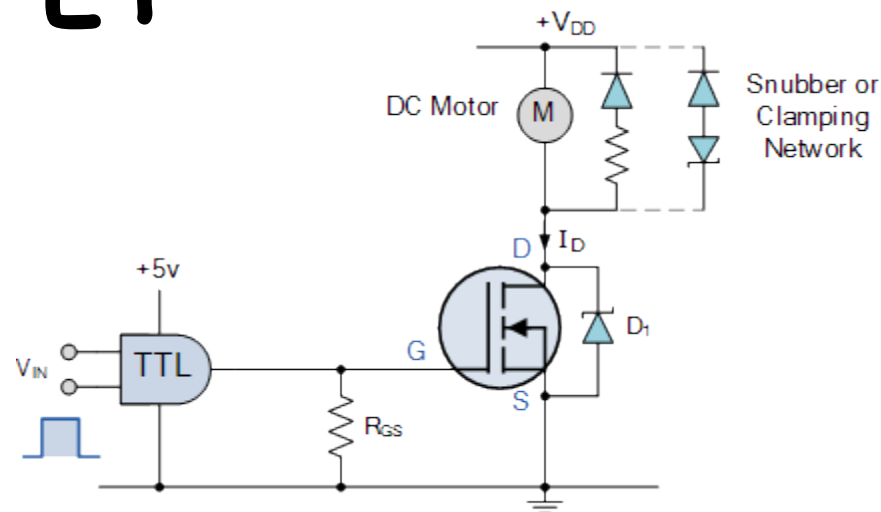
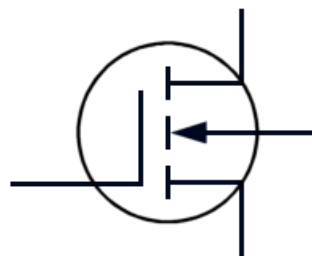


MOSFET

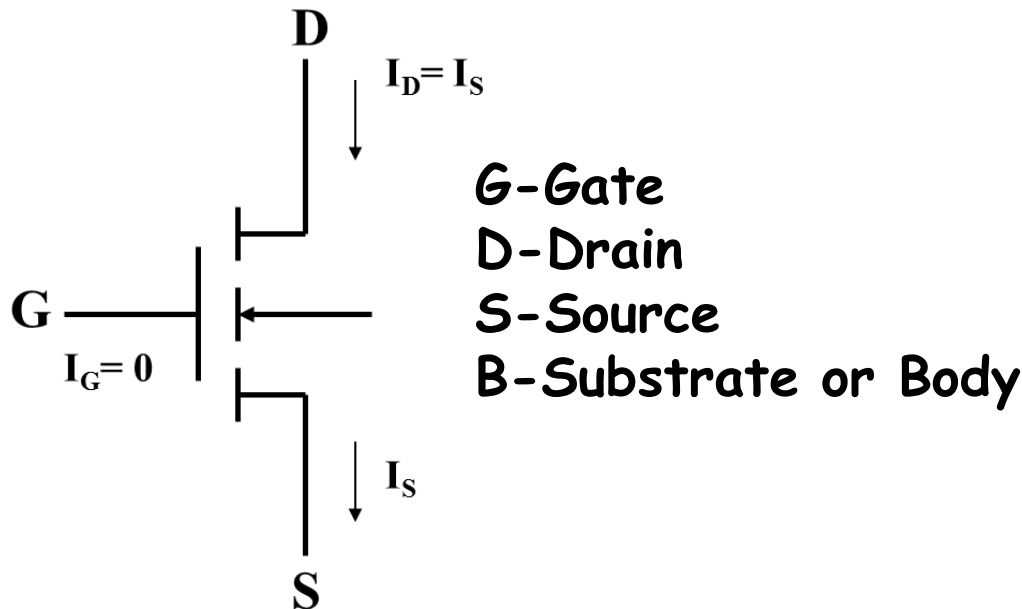


MOSFET

MOSFET stands for metal-oxide semiconductor field-effect transistor.

Unlike BJT which is 'current controlled', the MOSFET is a voltage controlled device.

The MOSFET has "gate", "Drain", "Source" and "Body" terminals.

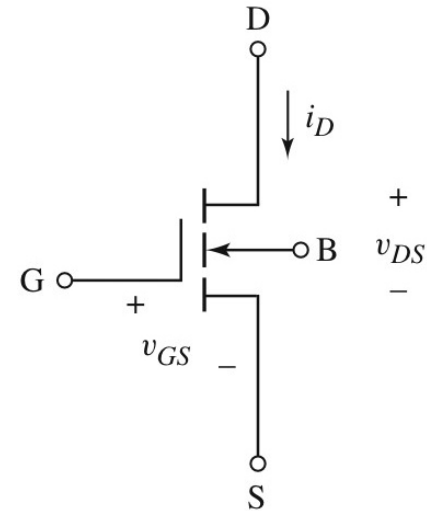


MOSFET

MOSFET - Metal-Oxide-Semiconductor Field Effect Transistor:

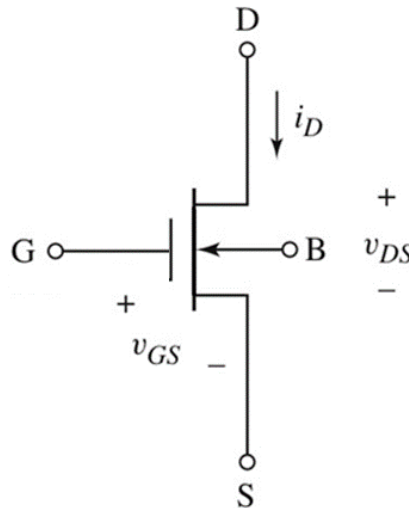
❖ Enhancement-type:

- n-channel (NMOS)
- p-channel (PMOS)



❖ Depletion-type:

- n-channel
- p-channel

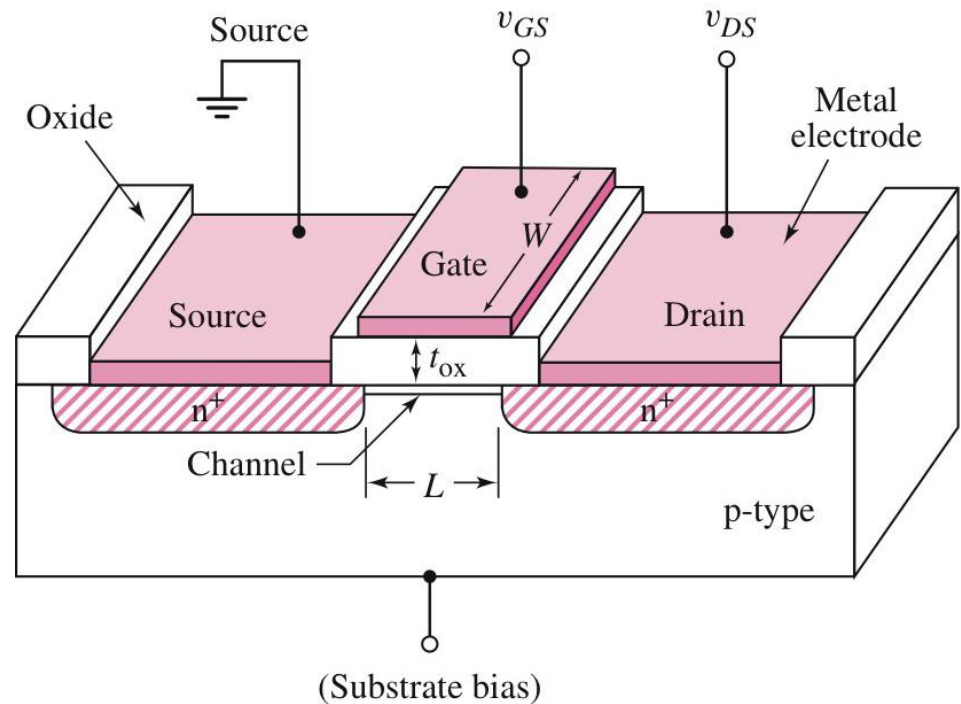


MOSFET

n-channel Enhancement-Type

Structure

- p-type substrate
- Two heavily-doped (n^+) regions created in the substrate to form the **drain** and the **source**.



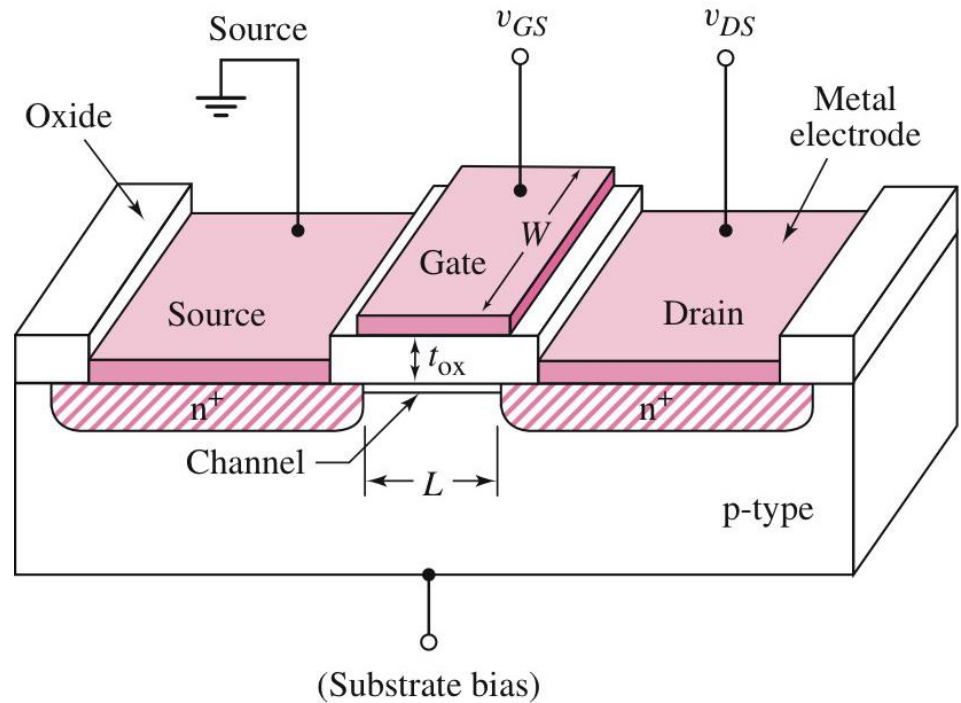
- A thin (0.02 to 0.1 μm) layer of silicon dioxide (SiO_2) is grown on the surface of the substrate covering the area between the source and the drain.

MOSFET

n-channel Enhancement-Type

Structure

- SiO_2 is an excellent insulator.
- Metal is deposited on the top of the SiO_2 layer to form the **gate** electrode.
- Metal contacts are also made to the source region, drain region and the substrate.
- Terminals are from these metal contacts which form the drain (**D**), source (**S**), gate (**G**) and substrate or body (**B**) terminals.

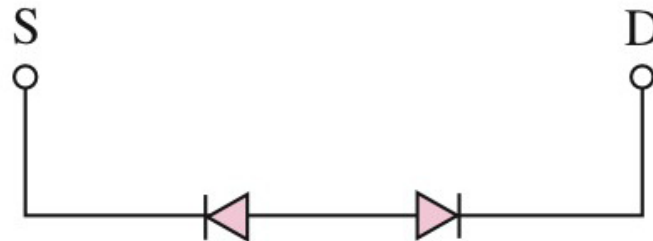
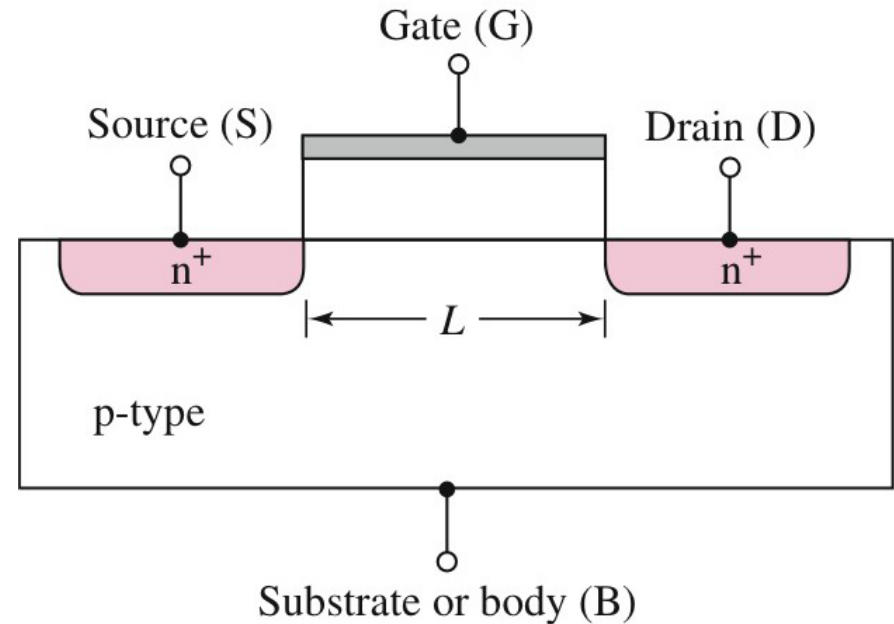


MOSFET

n-channel Enhancement-Type

Operation

- **With zero bias** at the gate, the source and the drain are separated by the p-region - equivalent to **two back-to-back diodes**.
- In this condition, the current is zero.

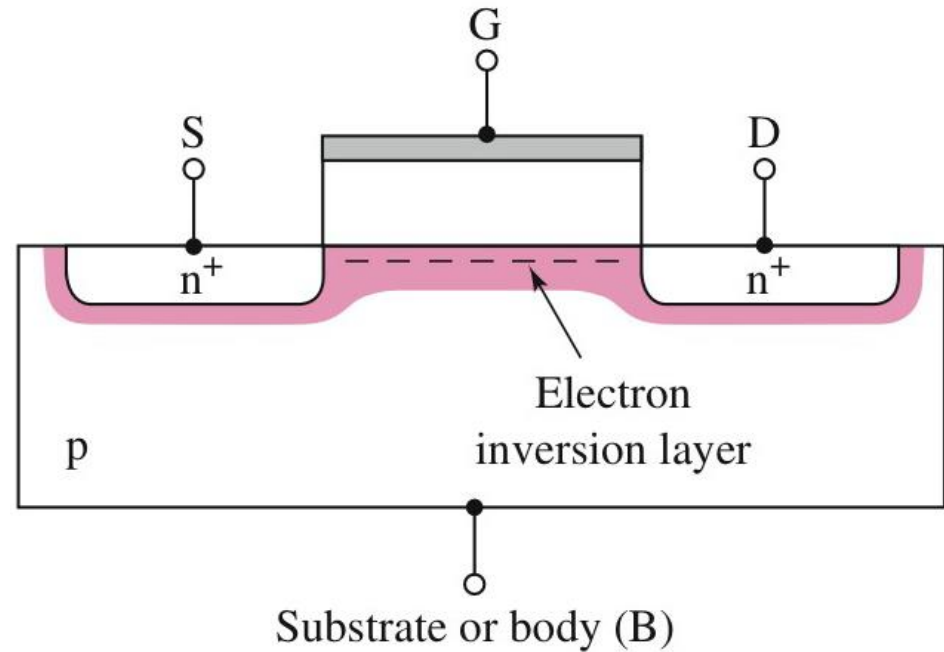


MOSFET

n-channel Enhancement-Type

Operation

- A gate voltage is required to create a conduction path.

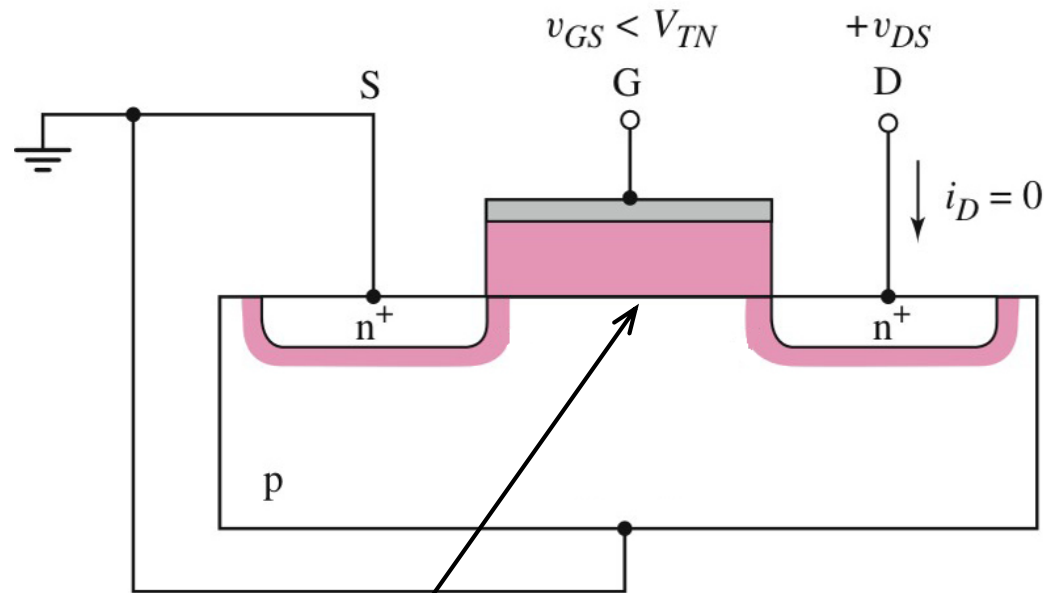


MOSFET

n-channel Enhancement-Type

Current-voltage characteristics

- In order to create *to create a conduction path between drain and source terminals*, the gate-to-source voltage (v_{GS}) must be applied to the gate of the transistor.
- This voltage must be above a minimum value known as the **threshold voltage (V_{TN})** which is positive for NMOS.



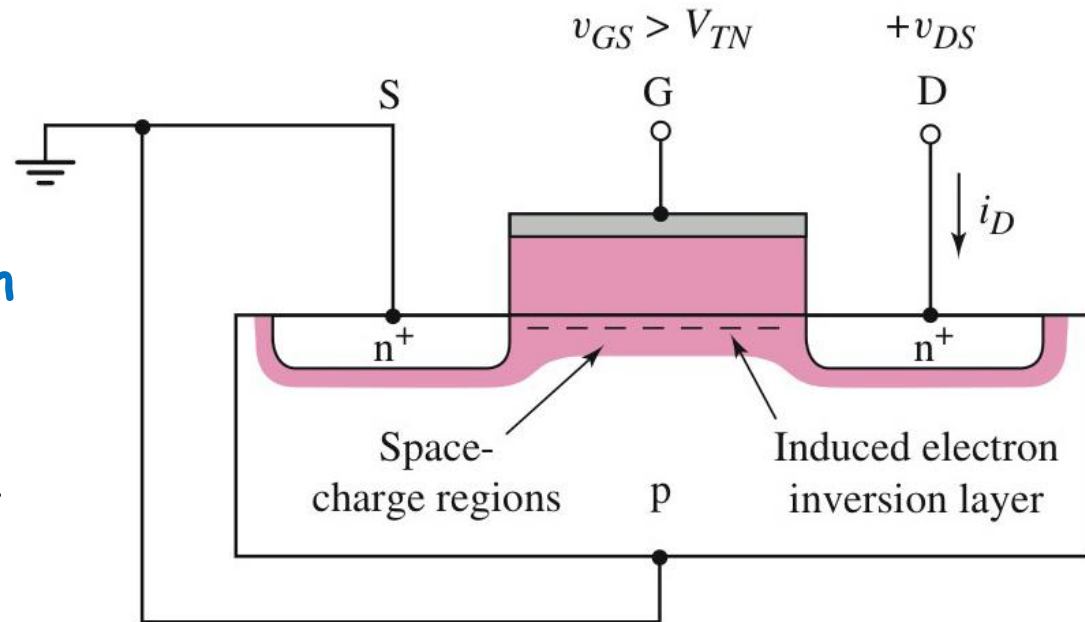
$v_{GS} < V_{TN}$ the channel is not formed

MOSFET

n-channel Enhancement-Type

Current-voltage characteristics

- When v_{GS} exceeds V_{TN} , the channel is formed.
- Current will flow if a voltage is applied between the drain and the source (v_{DS}). This current is known as the drain current (i_D)



Positive gate bias attracts electrons into channel.

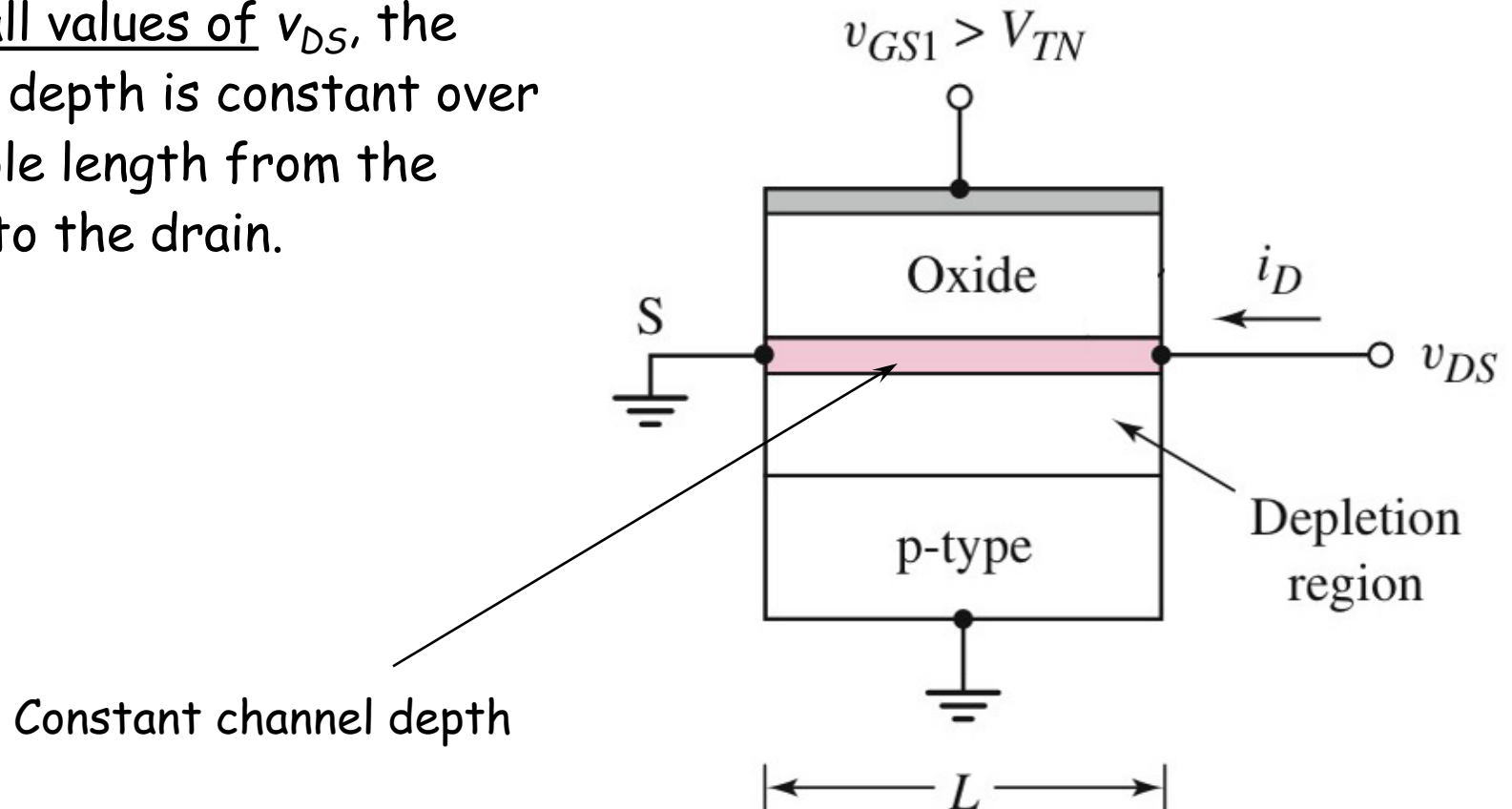
- The carriers in the conduction path are electrons - hence the term n-channel MOSFET (NMOS).

MOSFET

n-channel Enhancement-Type

Current-voltage characteristics

For small values of v_{DS} , the channel depth is constant over the whole length from the source to the drain.



MOSFET

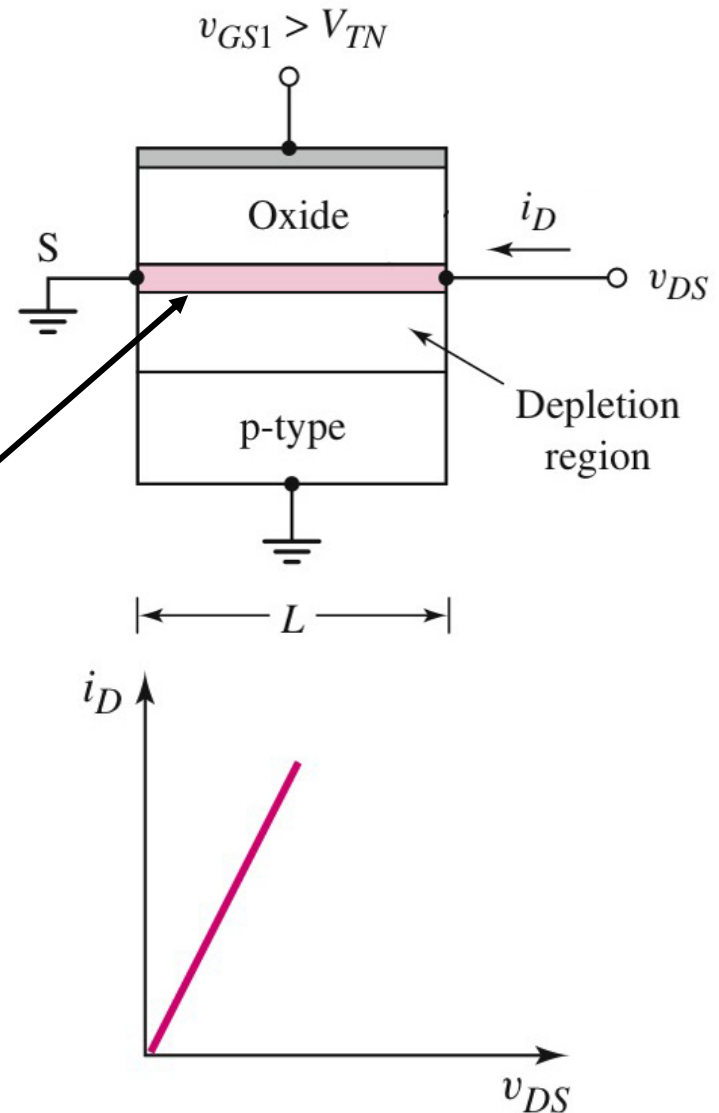
n-channel Enhancement-Type

Current-voltage characteristics

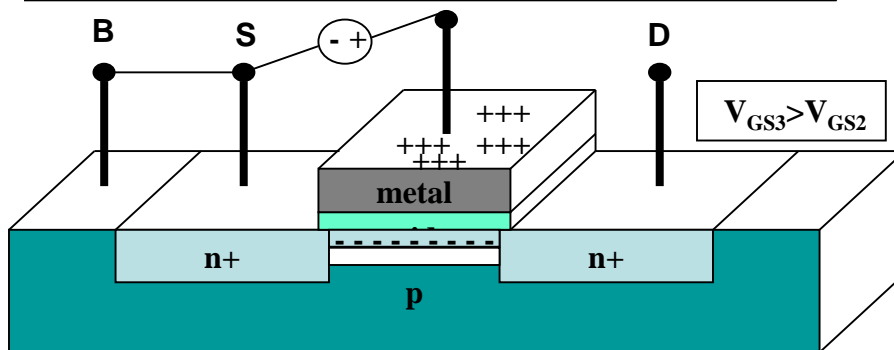
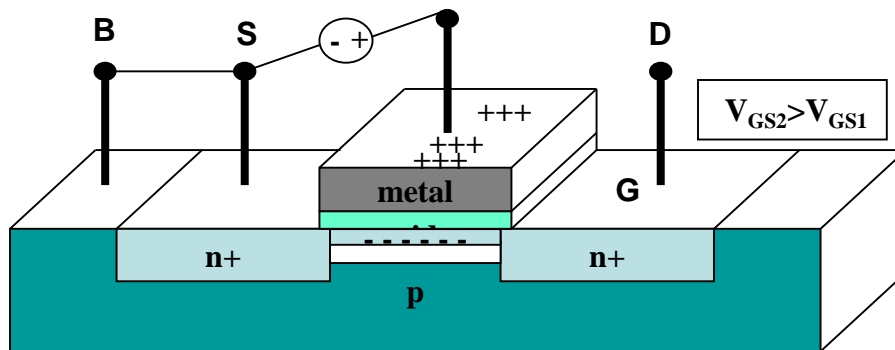
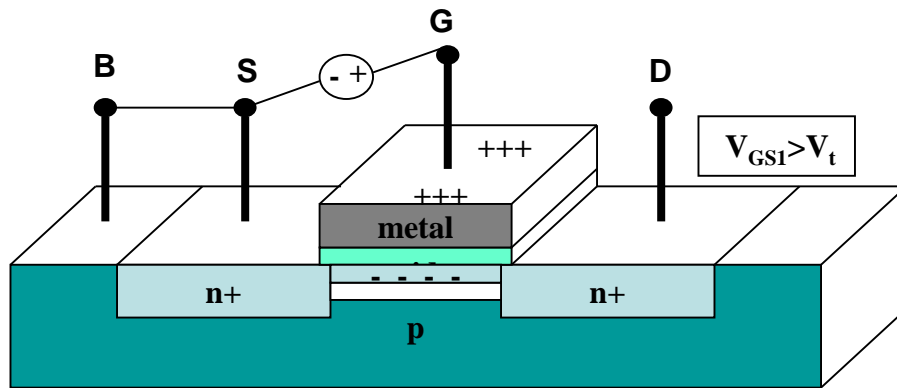
The constant channel depth causes the MOSFET to operate as a **linear resistance** (indicated by the linear relationship between i_D and v_{DS}) whose value is controlled by v_{GS} .

However, i_D is zero for $v_{GS} < V_{TN}$ for any value of v_{DS} .

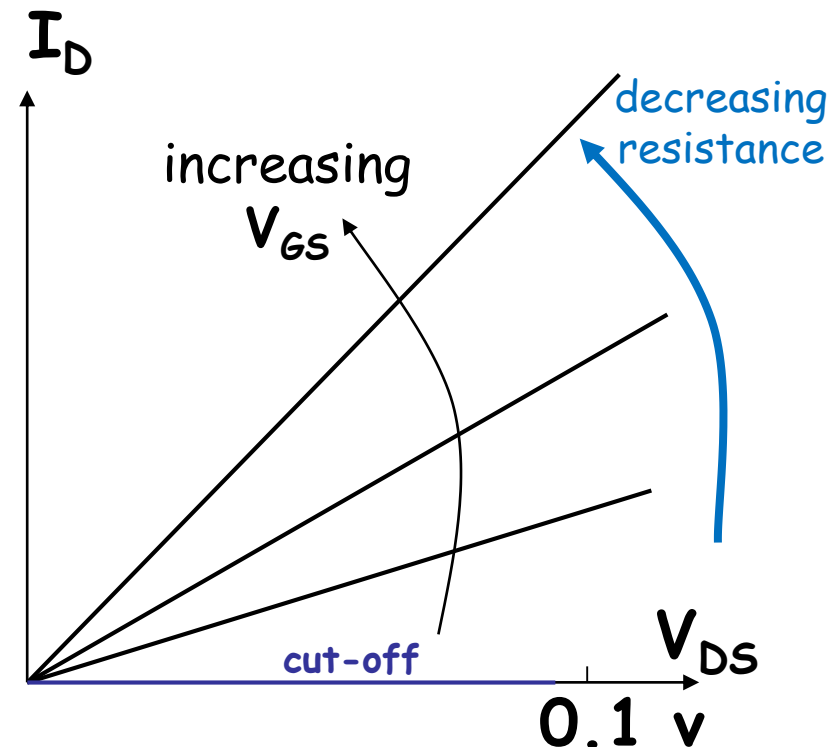
The constant channel depth



A voltage-controlled resistor @small V_{DS} (Enhancement mode)



Positive gate bias attracts electrons into channel.



Increasing V_{GS} puts more charge in the channel, allowing more drain current to flow.

MOSFET

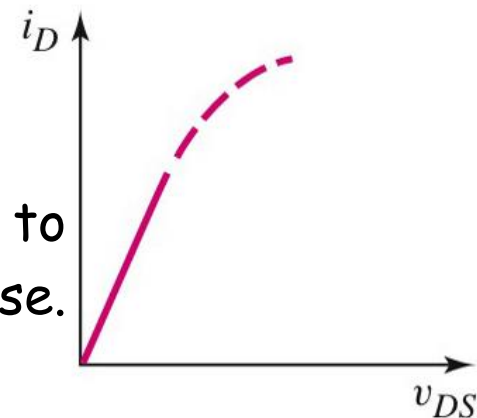
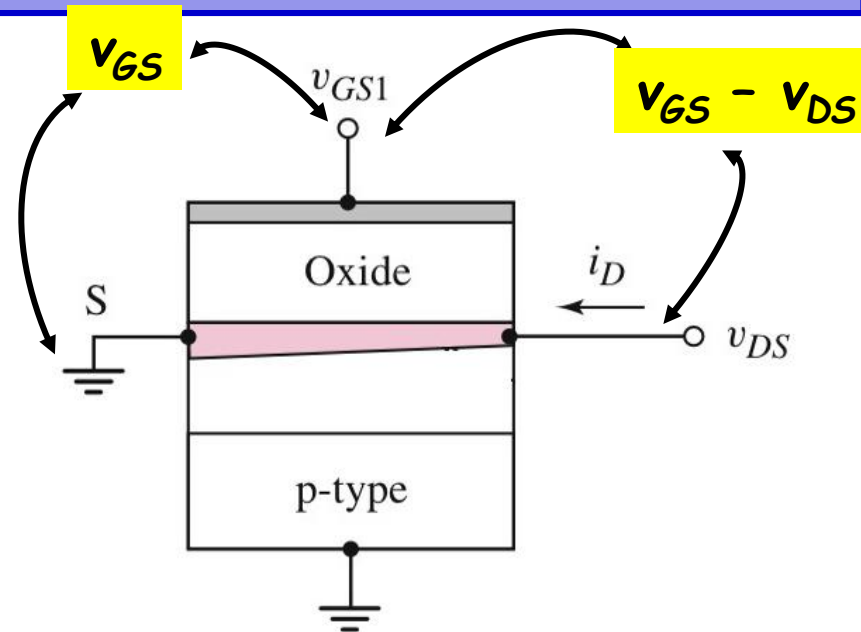
n-channel Enhancement-Type

Current-voltage characteristics

As the drain voltage increases, the voltage drop along the channel increases from 0 to v_{DS} .

The voltage between the gate and *the points along the channel* decreases from v_{GS} at the source end to $(v_{GS} - v_{DS})$ at the channel end, *resulting in a decrease in channel depth* at the drain (Figure).

This causes the conductivity to decrease.



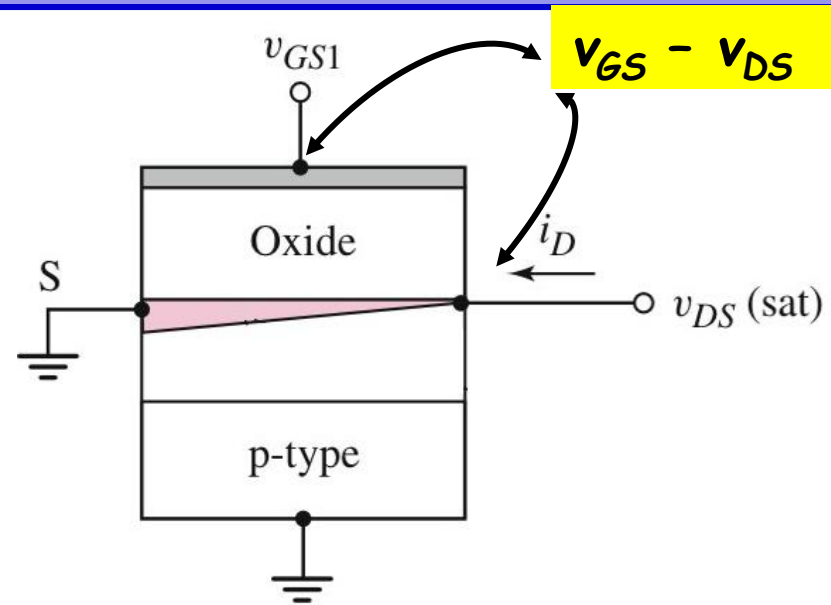
MOSFET

n-channel Enhancement-Type

Current-voltage characteristics

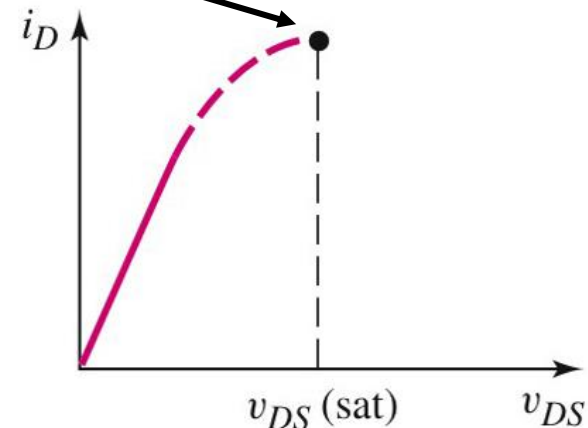
As the drain voltage increases to the point where $v_{GS} - v_{DS} = V_{TN}$, the channel depth will be zero.

The incremental conductivity is zero and the slope of the i_D versus v_{DS} curve is also zero. At the saturation point;



Or;

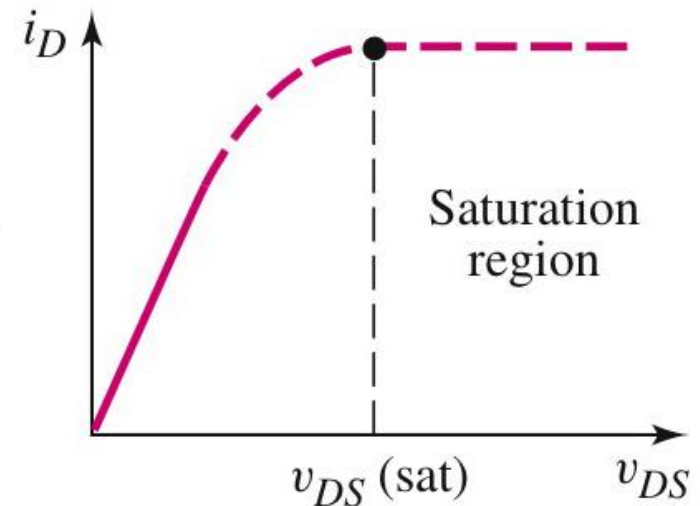
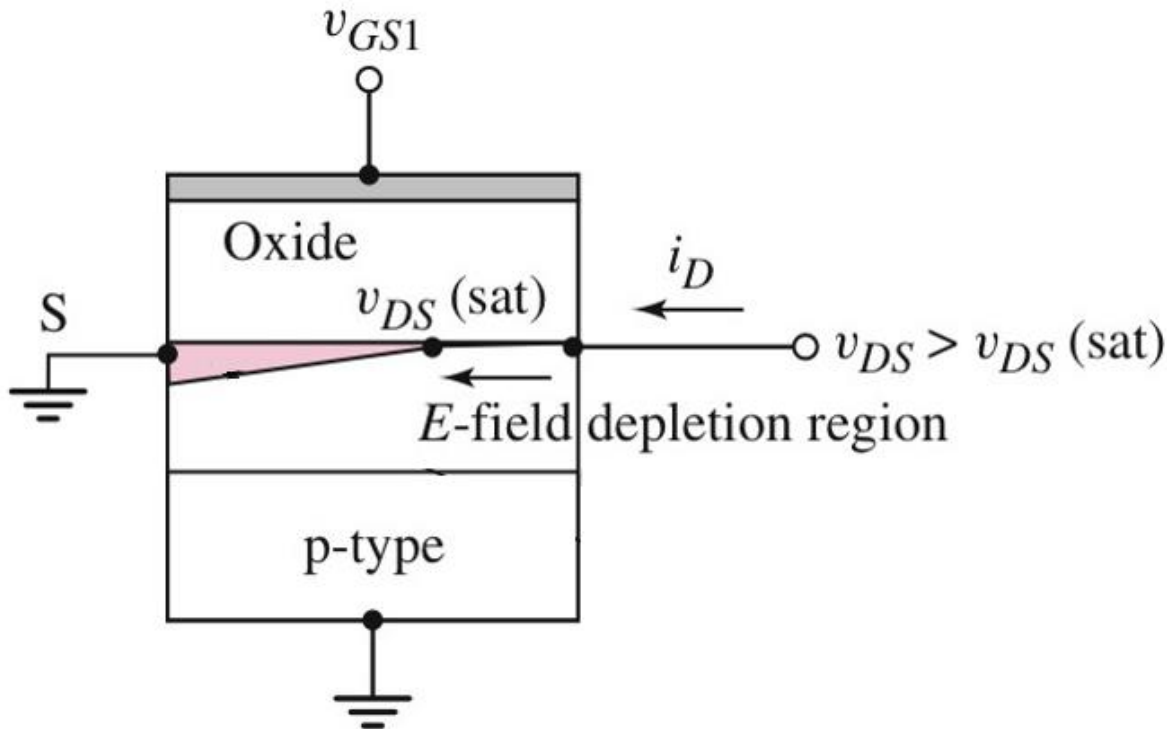
$$v_{GS} - v_{DS}(\text{sat}) = V_{TN}$$
$$v_{DS}(\text{sat}) = v_{GS} - V_{TN}$$



MOSFET

n-channel Enhancement-Type

Current-voltage characteristics



For $v_{DS} > v_{DS}(\text{sat})$, i_D is constant - **saturation region**

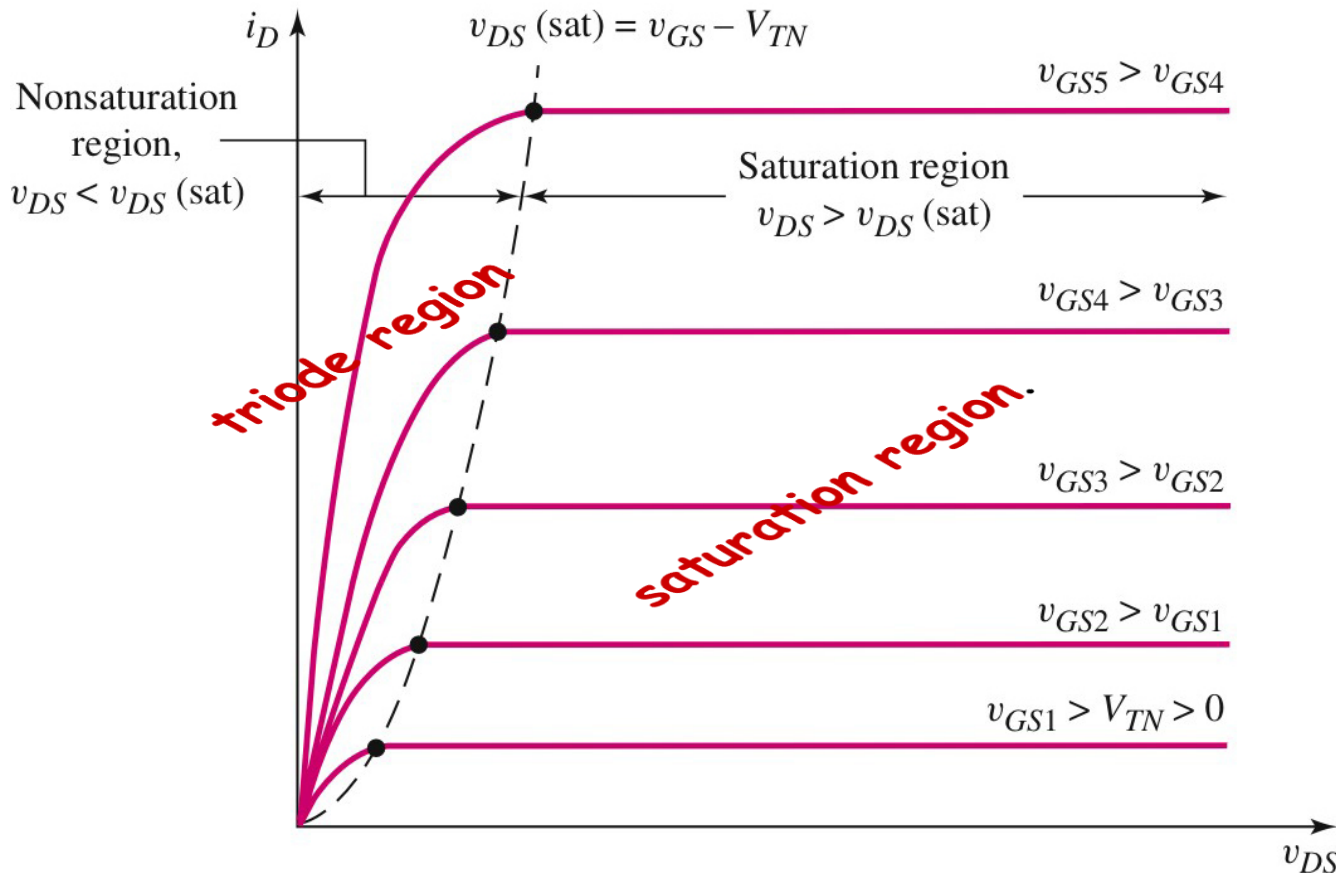
$$v_{DS}(\text{sat}) = v_{GS} - V_{TN}$$

MOSFET

n-channel Enhancement-Type

Current-voltage characteristics

As the v_{GS} increases, the i_D increases.



MOSFET

n-channel Enhancement-Type

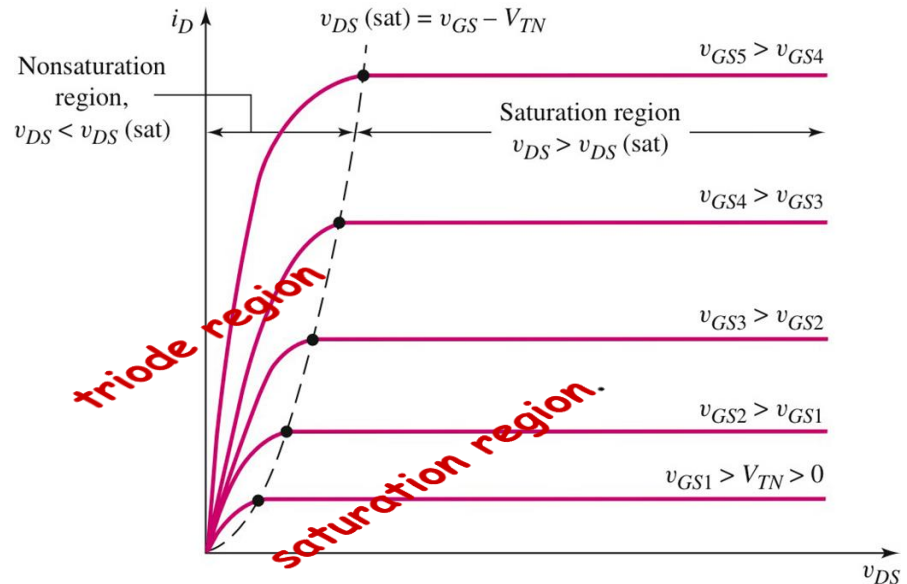
Current-voltage characteristics

The region where $v_{DS} < v_{DS}(\text{sat})$ is known as the **triode region**. For ideal MOSFET, the drain current i_D in this region is given by the expression;

$$i_D = K_n \left[2(v_{GS} - V_{TN})v_{DS} - v_{DS}^2 \right]$$

The region where $v_{DS} > v_{DS}(\text{sat})$ is known as the **saturation region**. The drain current i_D in this region is given by the expression;

$$i_D = K_n (v_{GS} - V_{TN})^2$$



MOSFET

n-channel Enhancement-Type

Current-voltage characteristics

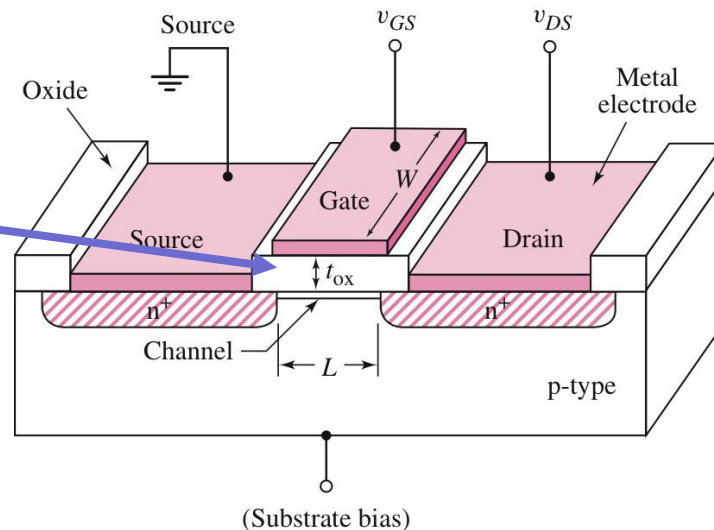
The parameter K_n is called **conduction parameter** which for NMOS, is given by the expression;

$$K_n = \frac{W\mu_n C_{ox}}{2L}$$

μ_n is the mobility of electrons in the SiO_2 layer and C_{ox} is the oxide capacitance per unit area given by the expression;

$$C_{ox} = \frac{\epsilon_{ox}}{t_{ox}}$$

ϵ_{ox} = oxide permittivity
 t_{ox} = oxide thickness



MOSFET

n-channel Enhancement-Type

Current-voltage characteristics

If we write;

$$k'_n = \mu_n C_{ox}$$

the expression for K_n becomes;

$$K_n = \frac{k'_n}{2} \cdot \frac{W}{L}$$

The expression for the drain current in the saturation region becomes;

$$i_D = \frac{1}{2} k'_n \frac{W}{L} (v_{GS} - V_{TN})^2$$

MOSFET

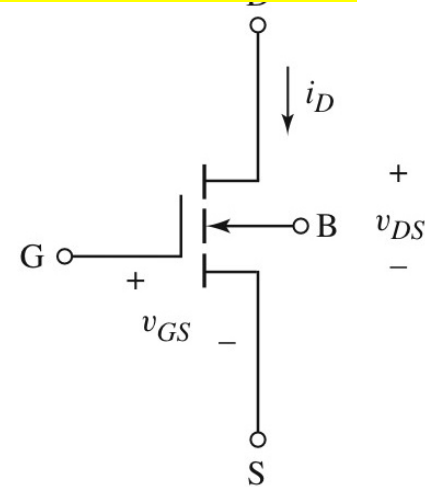
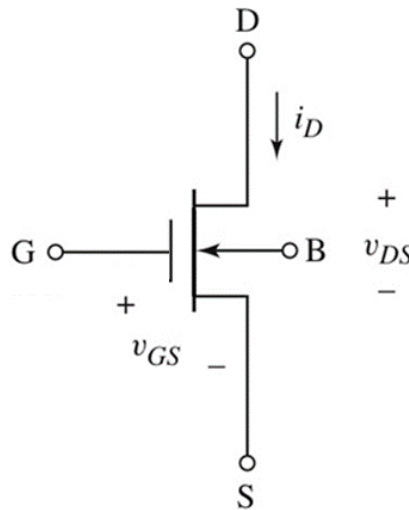
MOSFET - Metal-Oxide-Semiconductor Field Effect Transistor:

❖ Enhancement-type:

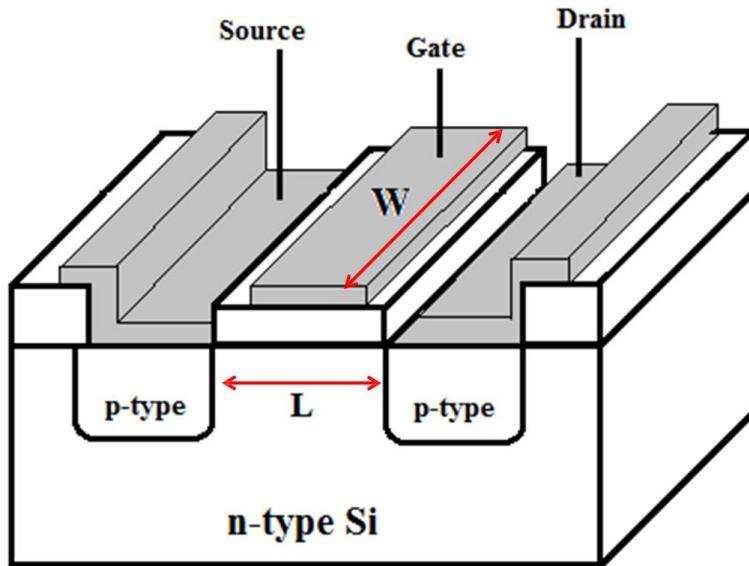
- n-channel (NMOS)
- p-channel (PMOS)

❖ Depletion-type:

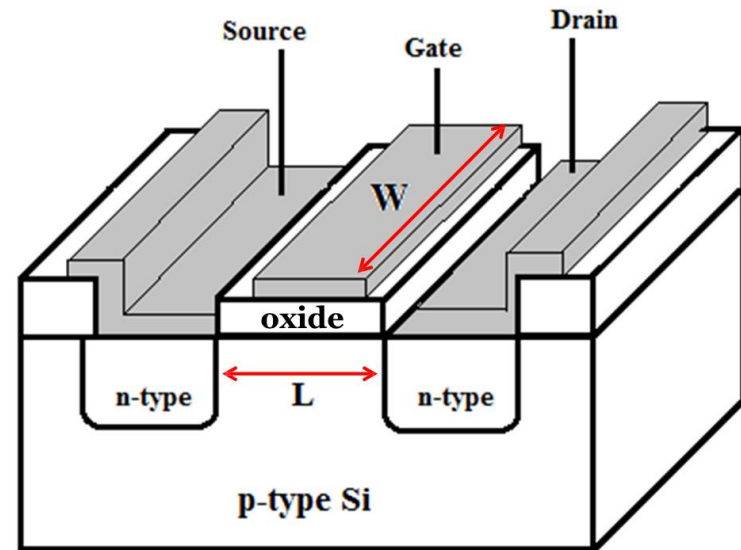
- n-channel
- p-channel



Cross-Sectional View of
p channel Enhancement Mode
Transistor



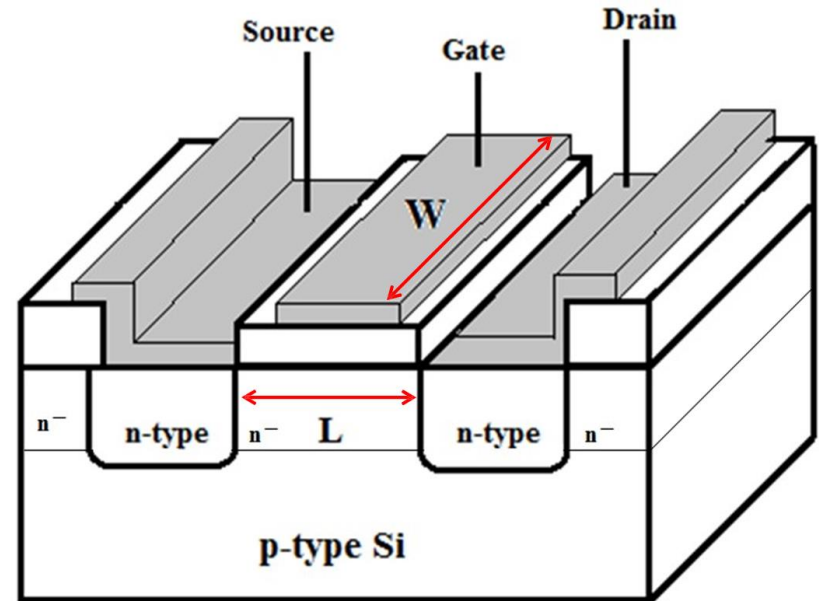
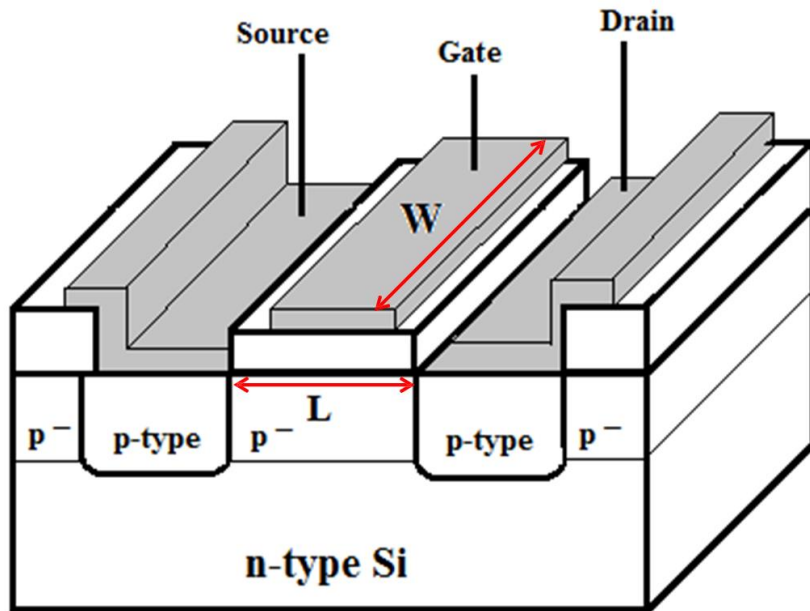
Cross-Sectional View of
n channel Enhancement Mode
Transistor



Enhancement mode

- Also known as Normally Off transistors.
 - A voltage (at least equal to the threshold voltage) must be applied to the gate of the transistor *to create a conduction path between the source and the drain of the transistor.*

p channel Depletion Mode Transistor n channel Depletion Mode Transistor



Depletion mode

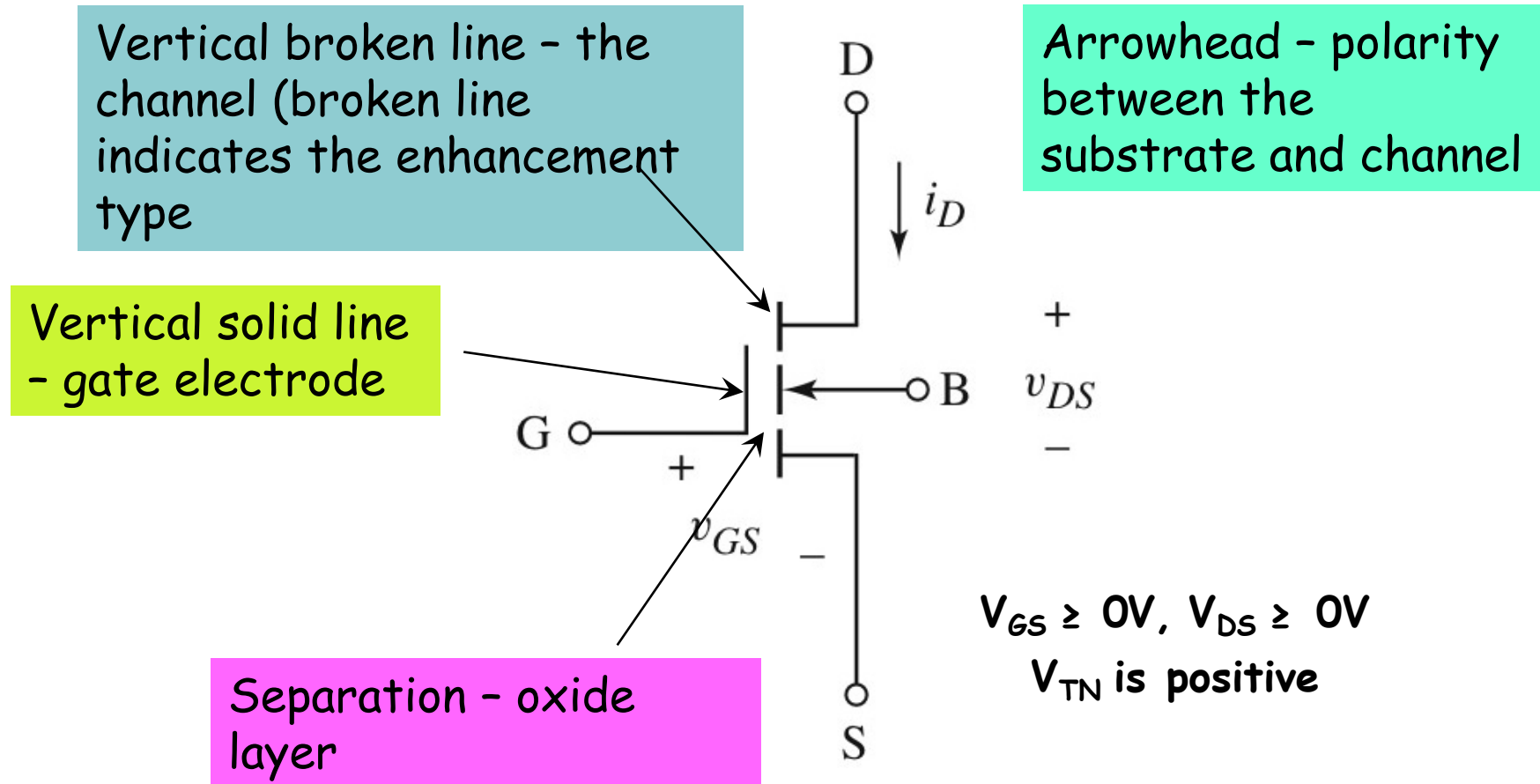
- Also known as Normally On transistors.
 - In order to prevent current from flowing between the source and drain,
 - a voltage (at least equal to the threshold voltage) must be applied to the gate of the transistor to
 - ***destroy the conduction path between the source and the drain.***

MOSFET

n-channel Enhancement-Type

Circuit symbols and Conventions

Conventional symbol



MOSFET

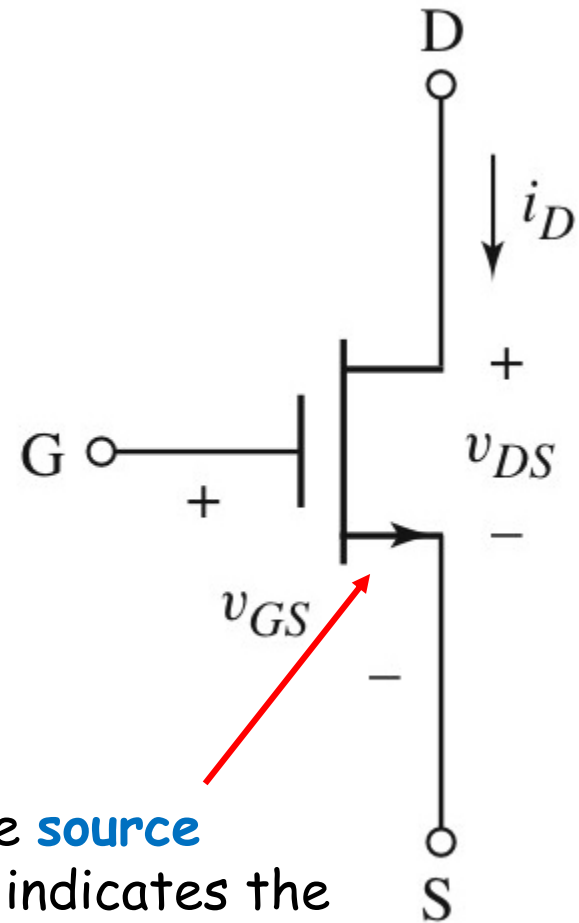
n-channel Enhancement-Type

Circuit symbols and Conventions

In many cases, the substrate and source terminals are connected together. The circuit symbol can be simplified.

$$V_{GS} \geq 0V, V_{DS} \geq 0V$$

V_{TN} is positive

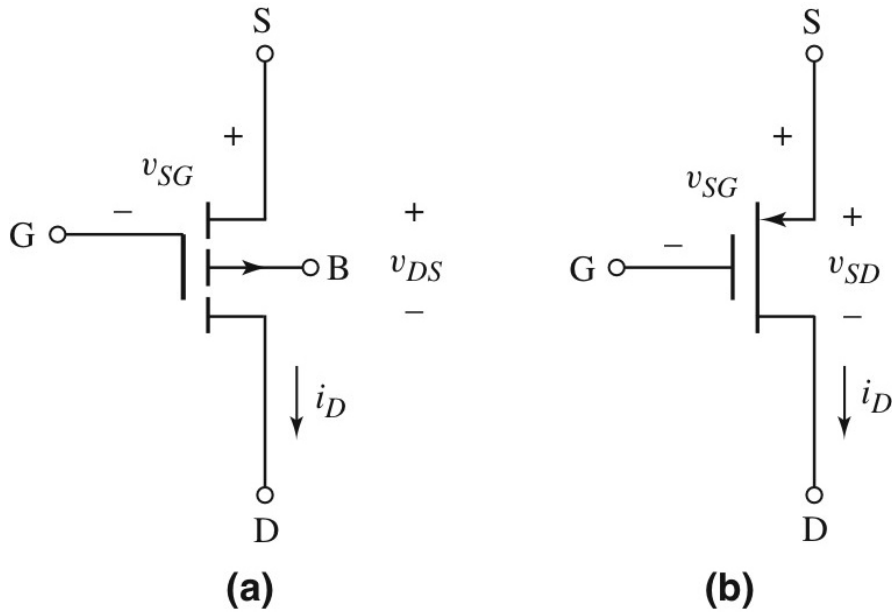


The arrowhead is in the **source terminal** and direction indicates the direction of current.

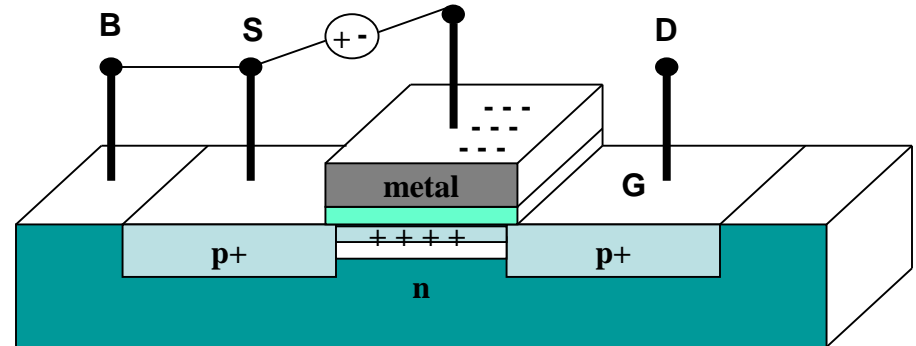
MOSFET

p-channel Enhancement-Type

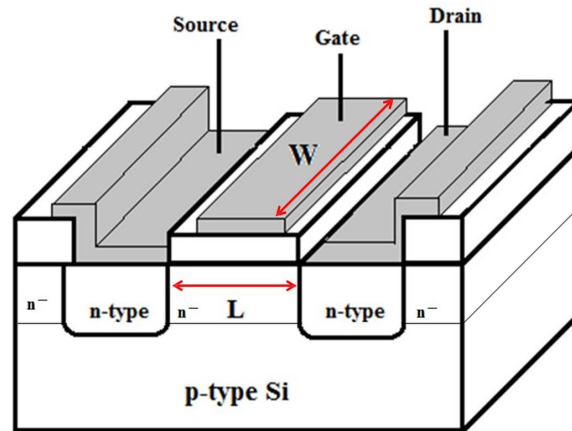
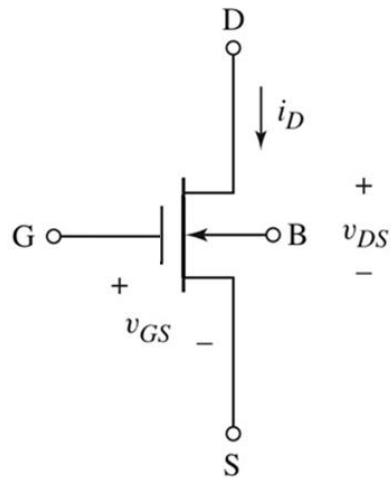
Circuit symbols and Conventions



$V_{GS} \leq 0V, V_{DS} \leq 0V$
 V_{TP} is negative

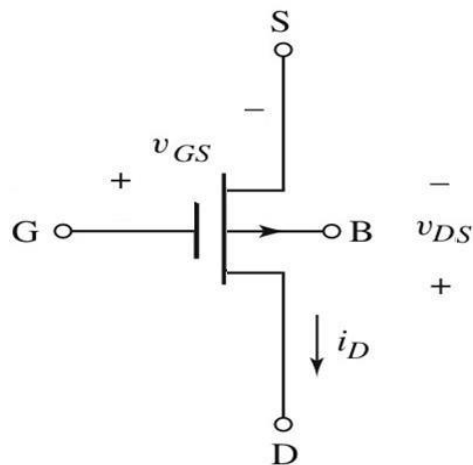


Symbols for n channel **Depletion Mode** MOSFET



in order to destroy the channel, gate voltage must be negative and less than the threshold voltage

Symbols for p channel **Depletion Mode** MOSFET



An enhancement MOSFET and a depletion MOSFET are **precisely** identical in **nearly** every way (e.g., same **modes**, same **equations**, same **terminal** names).

Except: The **threshold voltage** for a depletion **NMOS** device is **negative** (i.e., $V_t < 0$). While the threshold voltage for a depletion **PMOS** device is **positive** (i.e., $V_t > 0$).

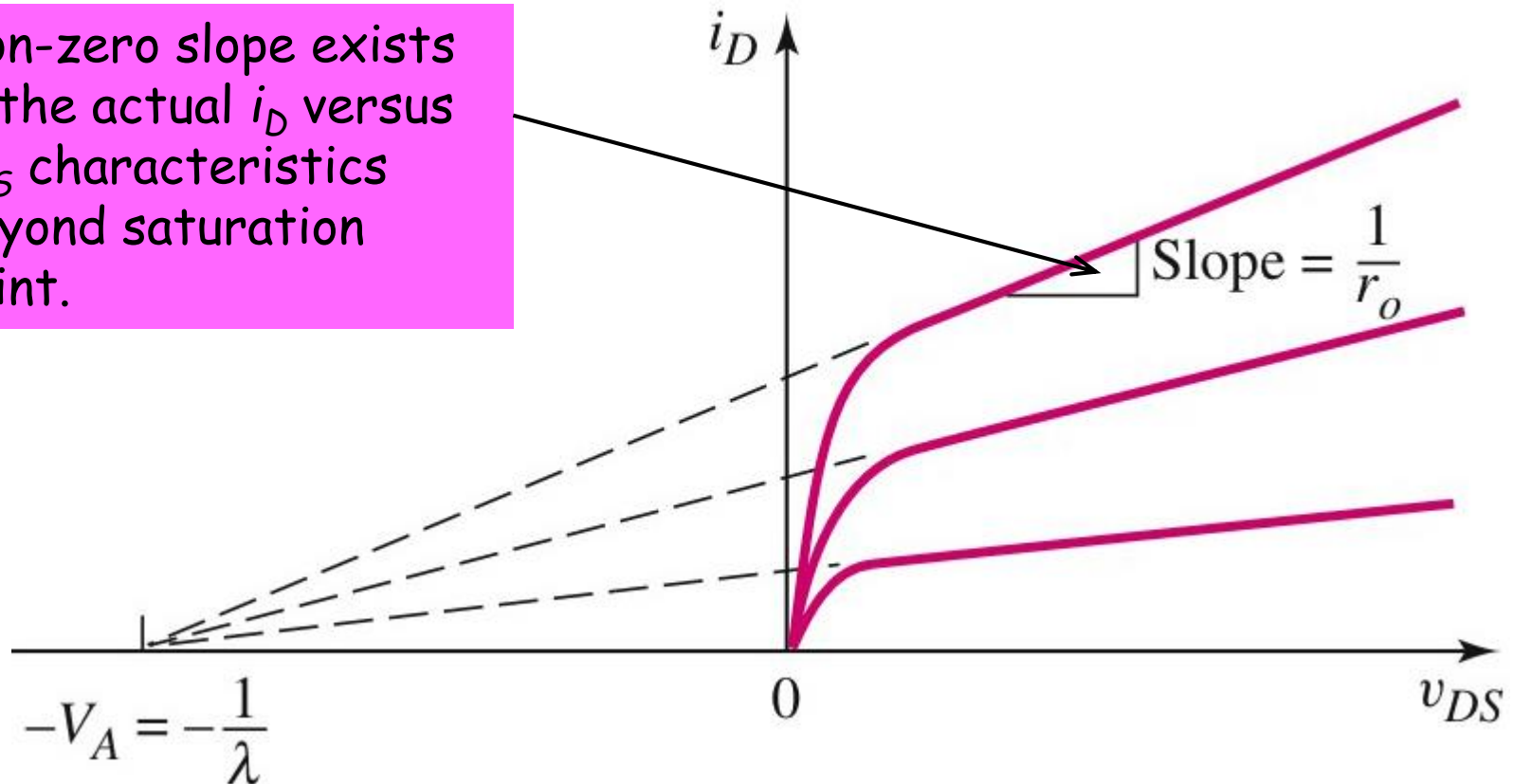
MOSFET

n-channel Enhancement-Type

Non-ideal Current-voltage characteristics

The drain current i_D is dependent on the drain-to-source voltage v_{DS} due to **channel length modulation**.

Non-zero slope exists in the actual i_D versus v_{DS} characteristics beyond saturation point.



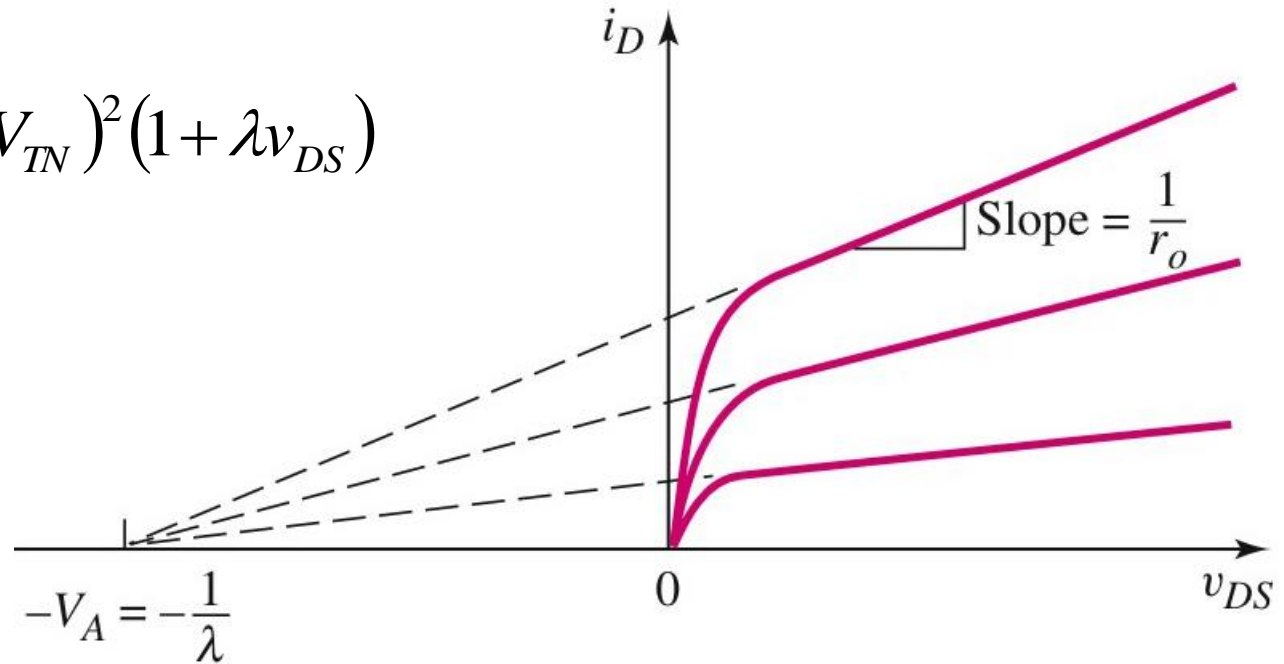
MOSFET

n-channel Enhancement-Type

Non-ideal Current-voltage characteristics

In the saturation region, the drain current may expressed as;

$$i_D = K_n (v_{GS} - V_{TN})^2 (1 + \lambda v_{DS})$$

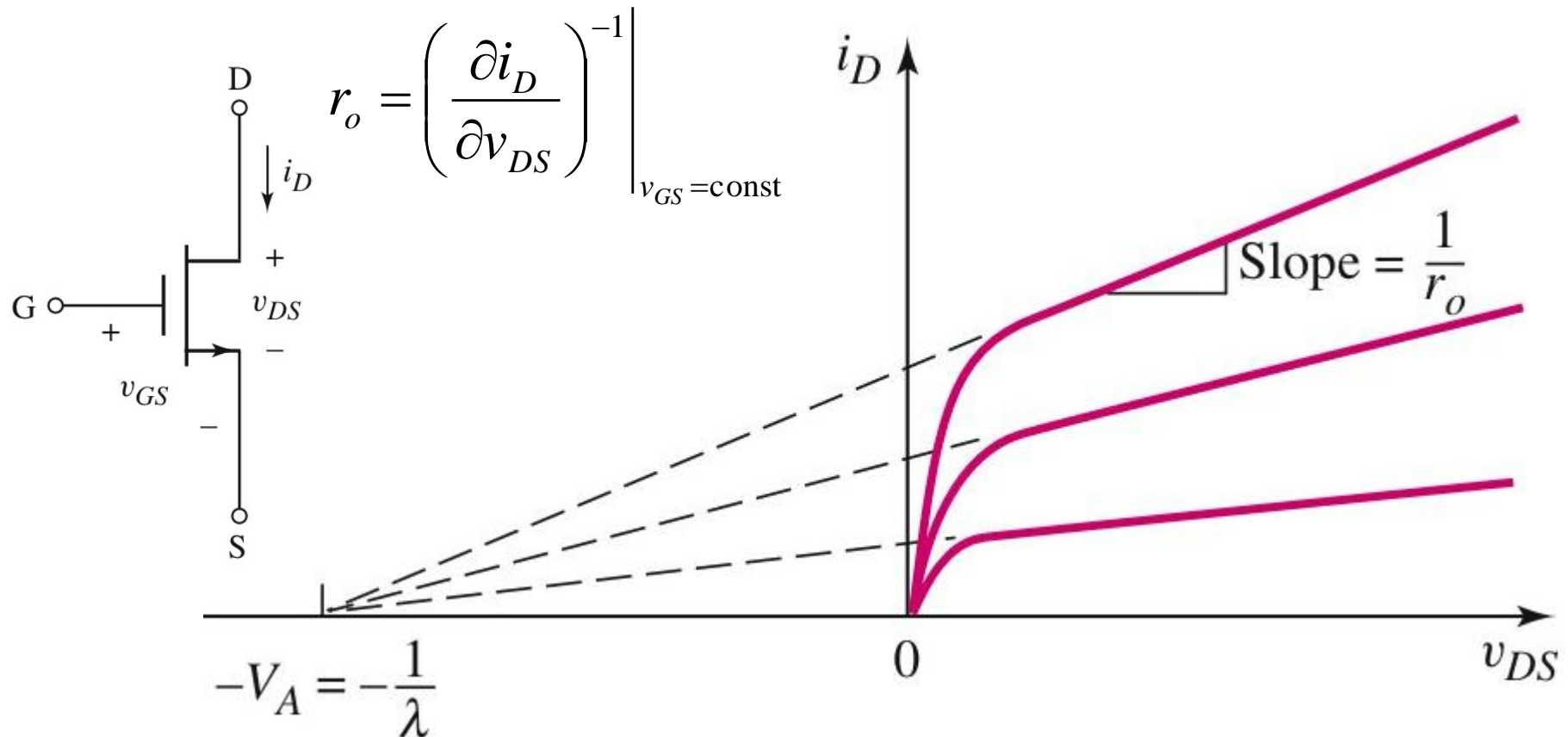


MOSFET

n-channel Enhancement-Type

Non-ideal Current-voltage characteristics

The output resistance r_o is the inverse of the slope of the characteristics curves;



MOSFET

n-channel Enhancement-Type

Non-ideal Current-voltage characteristics

Differentiating the expression for i_{DS} at the Q-point, gives us;

$$r_o = \left(\frac{\partial i_D}{\partial v_{DS}} \right)^{-1} \bigg|_{v_{GS} = \text{const}} \quad i_D = K_n (v_{GS} - V_{TN})^2 (1 + \lambda v_{DS})$$

$$r_o = \left[\lambda K_n (V_{GSQ} - V_{TN})^2 \right]^{-1}$$

or

$$r_o \cong \left[\lambda I_{DQ} \right]^{-1} = \frac{1}{\lambda I_{DQ}} = \frac{V_A}{I_{DQ}}$$